

Supplementary information

Polyoxometalate-Ionic Liquids (POM-ILs) - a new type of ionic liquids for lubricants

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Supplementary information

1- Friction evolution of the different lubricant blends

1.1 - DPG

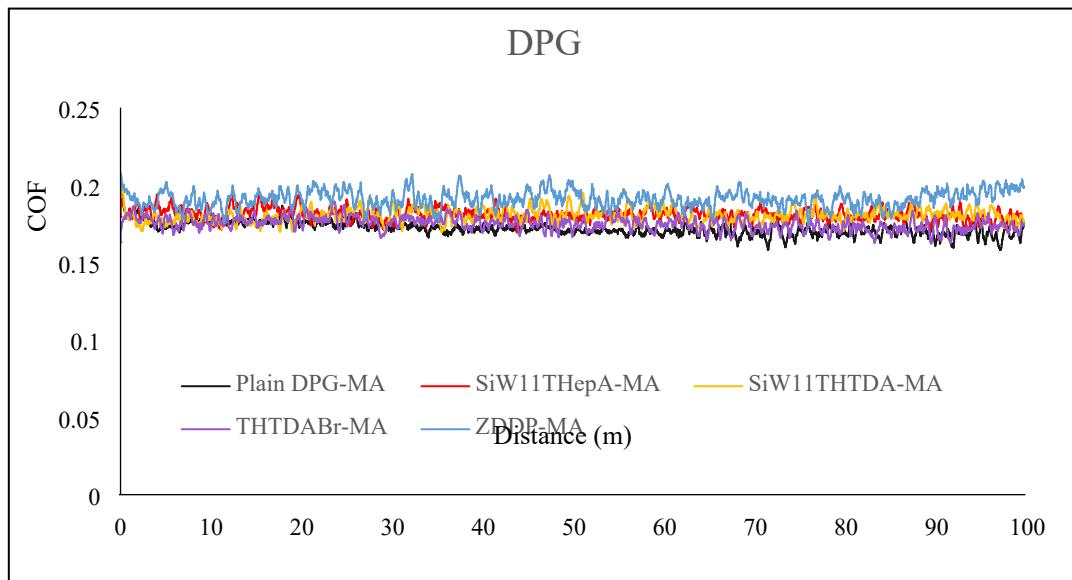


Figure S1. Friction evolution behaviour of different additives in DPG as well as plain DPG.

1.2 - DEG

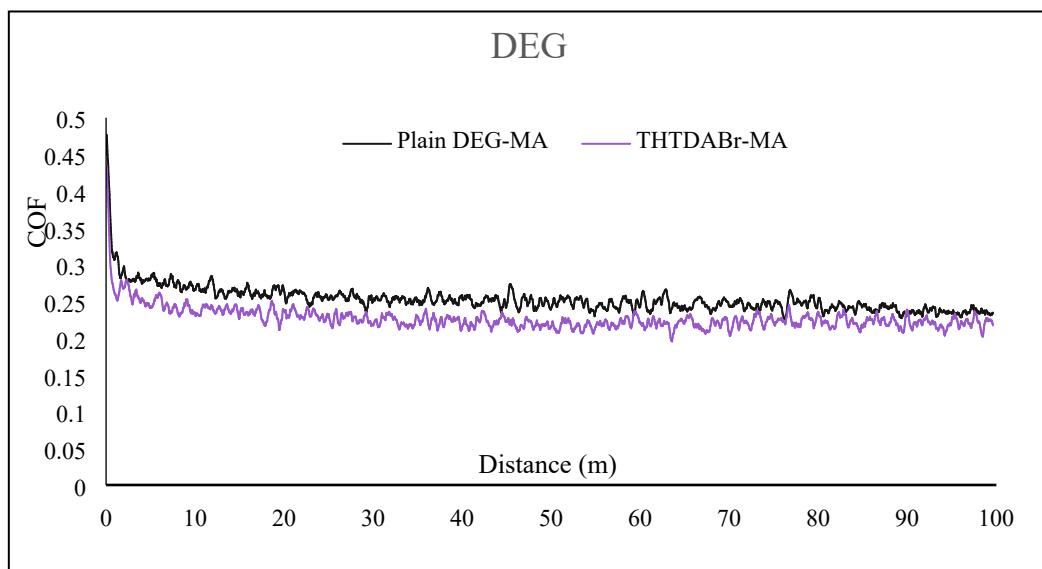


Figure S2. Friction evolution behaviour of different additives in DEG as well as plain DEG.

Supplementary information

1.3 - DhL 4016

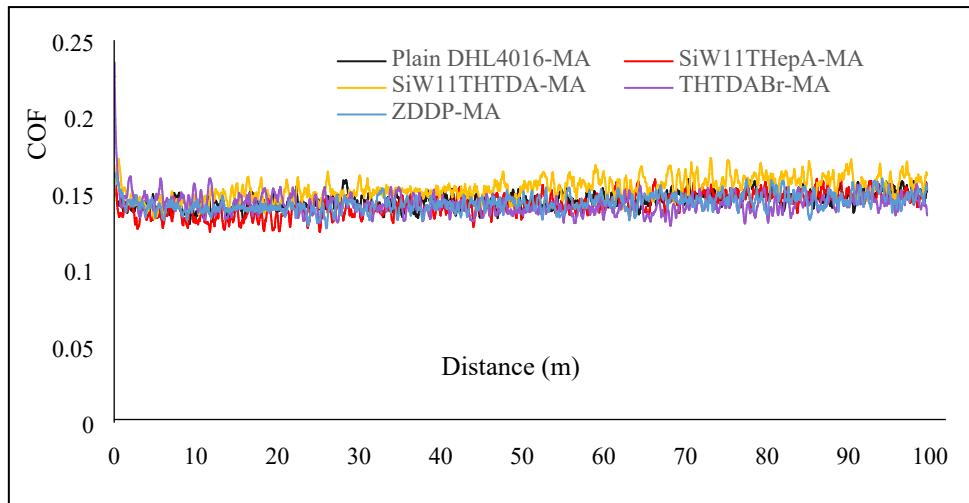


Figure S3. Friction evolution behaviour of different additives in DhL 4016 as well as plain DhL 4016.

1.4 - DhL 4018

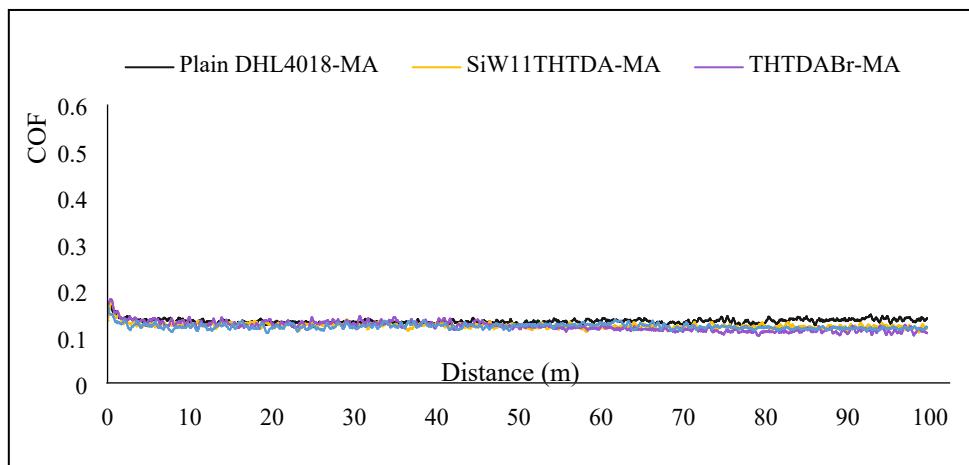


Figure S4. Friction evolution behaviour of different additives in DhL 4018 as well as plain DhL 4018.

1.5 - PAO 8

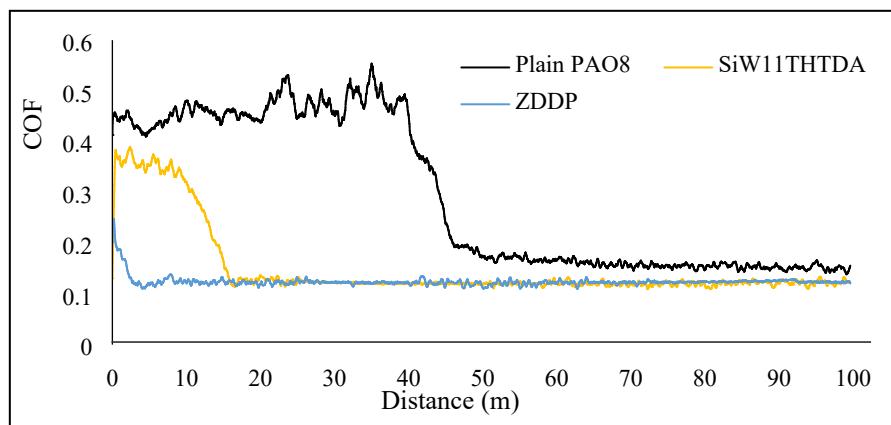
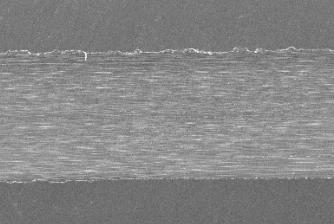
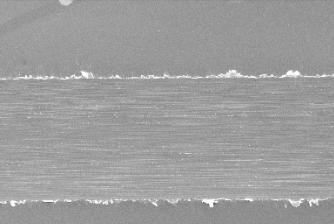
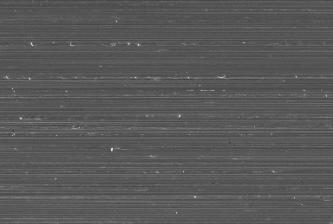
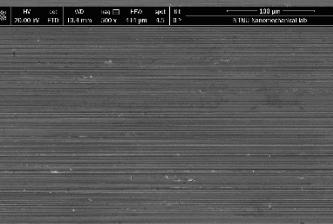
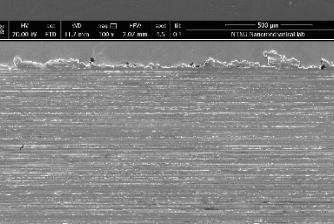
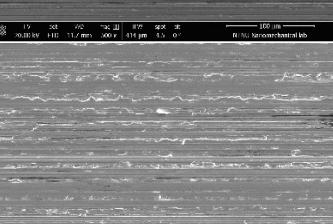


Figure S5. Friction evolution behaviour of different additives in PAO 8 as well as plain PAO 8.

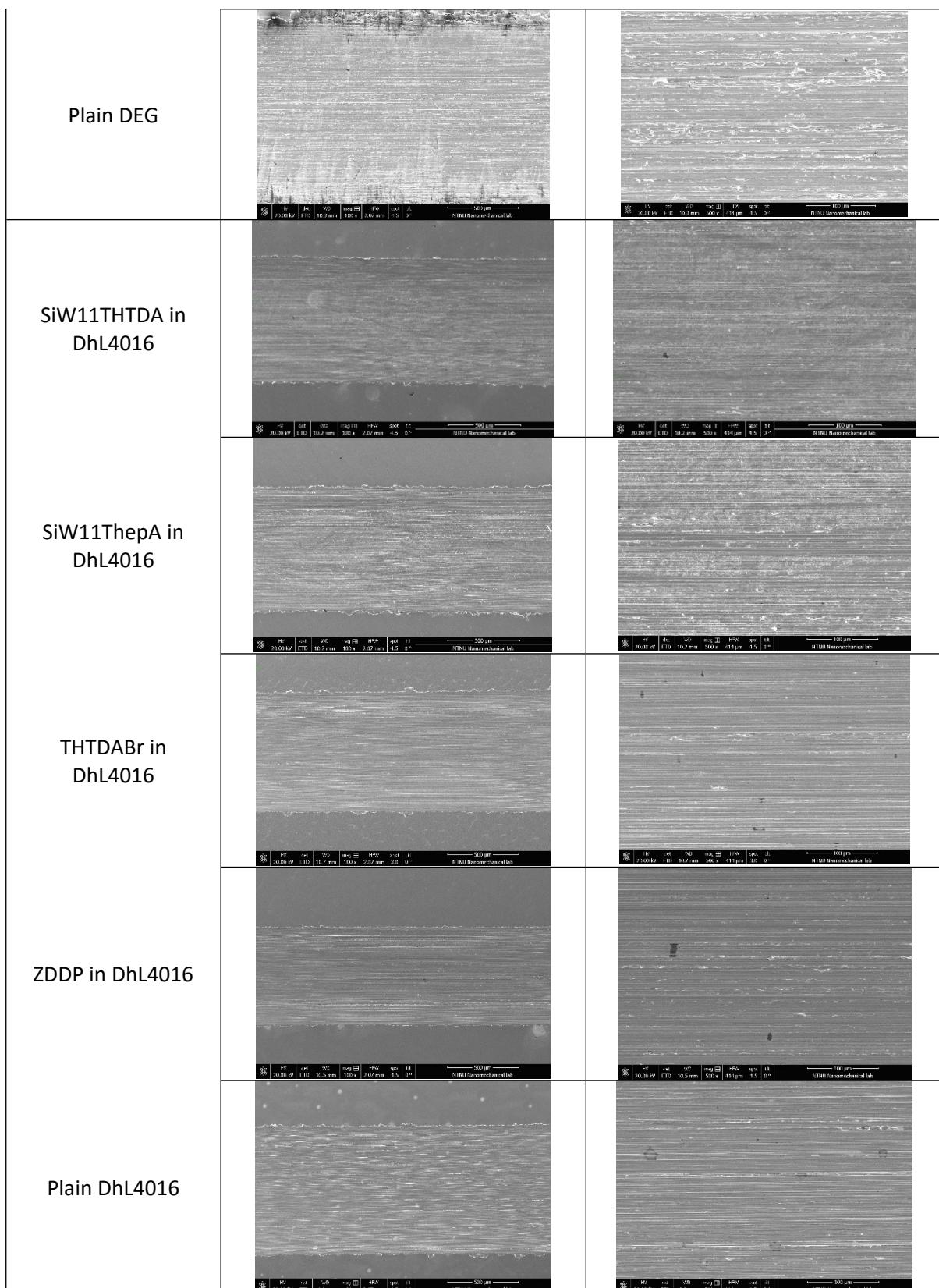
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2- Top view SEM images the different blends tested on AISI 316L

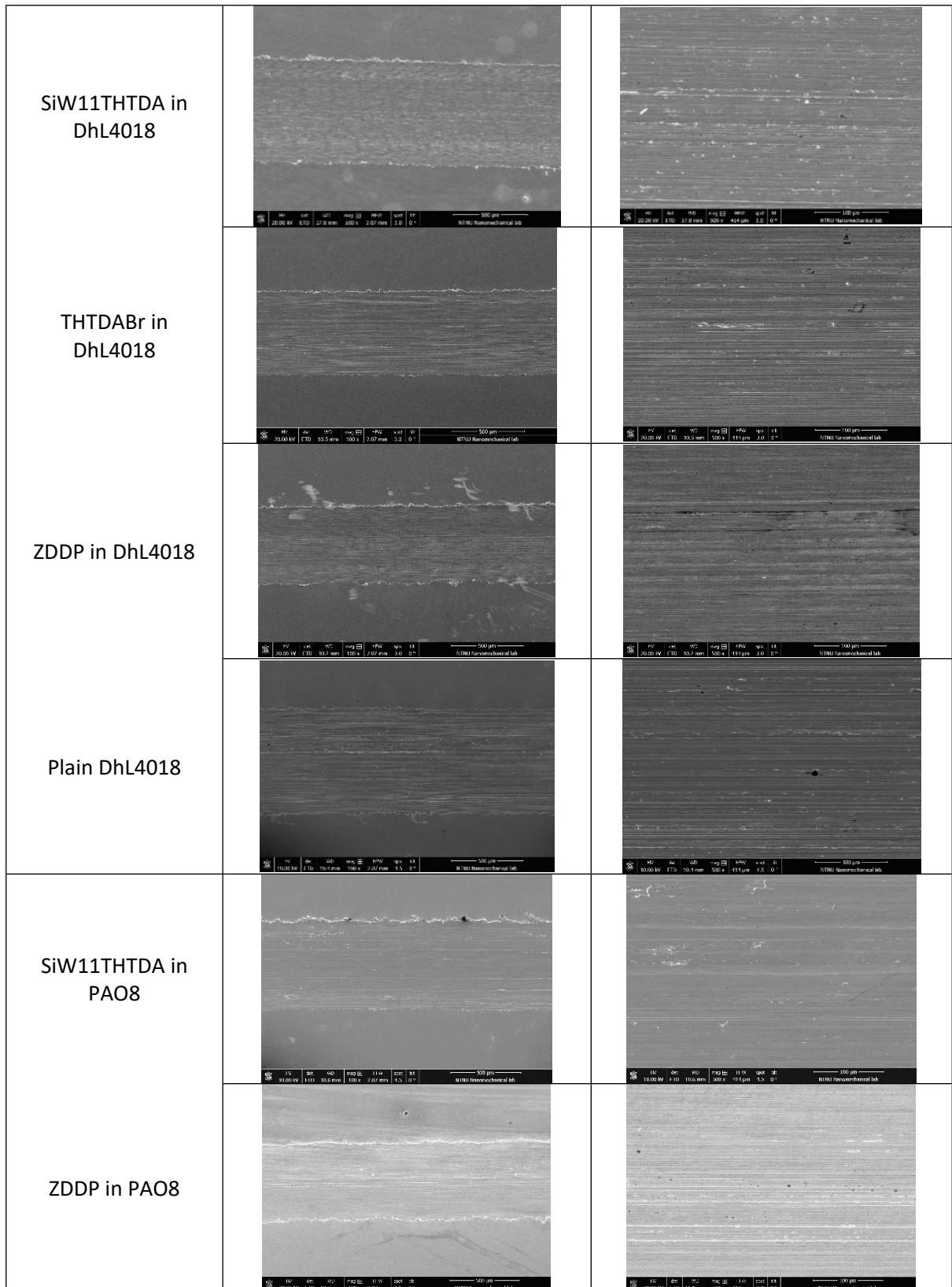
Table S1. SEM images of the wear track surface on the AISI 316L stainless steel discs for all the different lubricant blends tested at both 100 and 500 magnification.

Lubricant blend	x100	x500
SiW11THTDA in DPG	 50° 10° 60° 0° 100° 100V 1.0μm 4.5° 0.1 100 μm 50° 20.00 kV FIB 13.1 nm 100V 1.0μm 4.5° 0.1 100 μm MTU-Hannover Material Lab	 50° 10° 60° 0° 100° 100V 1.0μm 4.5° 0.1 100 μm 50° 20.00 kV FIB 13.1 nm 100V 1.0μm 4.5° 0.1 100 μm MTU-Hannover Material Lab
SiW11ThepA in DPG	 50° 10° 60° 0° 100° 100V 2.0μm 3.0° 0.1 500 μm 50° 20.00 kV FIB 17.8 nm 100V 2.0μm 3.0° 0.1 500 μm MTU-Hannover Material Lab	 50° 10° 60° 0° 100° 100V 2.0μm 3.0° 0.1 500 μm 50° 20.00 kV FIB 17.8 nm 100V 2.0μm 3.0° 0.1 500 μm MTU-Hannover Material Lab
THTDABr in DPG	 50° 10° 60° 0° 100° 100V 2.0μm 3.0° 0.1 500 μm 50° 20.00 kV FIB 17.8 nm 100V 2.0μm 3.0° 0.1 500 μm MTU-Hannover Material Lab	 50° 10° 60° 0° 100° 100V 2.0μm 3.0° 0.1 500 μm 50° 20.00 kV FIB 17.8 nm 100V 2.0μm 3.0° 0.1 500 μm MTU-Hannover Material Lab
ZDDP in DPG	 50° 10° 60° 0° 100° 100V 2.0μm 3.0° 0.1 500 μm 50° 20.00 kV FIB 16.4 nm 100V 2.0μm 3.0° 0.1 500 μm MTU-Hannover Material Lab	 50° 10° 60° 0° 100° 100V 2.0μm 3.0° 0.1 500 μm 50° 20.00 kV FIB 16.4 nm 100V 2.0μm 3.0° 0.1 500 μm MTU-Hannover Material Lab
Plain DPG	 50° 10° 60° 0° 100° 100V 2.0μm 3.0° 0.1 500 μm 50° 20.00 kV FIB 11.7 nm 100V 2.0μm 3.0° 0.1 500 μm MTU-Hannover Material Lab	 50° 10° 60° 0° 100° 100V 2.0μm 3.0° 0.1 500 μm 50° 20.00 kV FIB 11.7 nm 100V 2.0μm 3.0° 0.1 500 μm MTU-Hannover Material Lab
THTDABr in DEG	 50° 10° 60° 0° 100° 100V 2.0μm 3.0° 0.1 500 μm 50° 20.00 kV FIB 10.1 nm 100V 2.0μm 3.0° 0.1 500 μm MTU-Hannover Material Lab	 50° 10° 60° 0° 100° 100V 2.0μm 3.0° 0.1 500 μm 50° 20.00 kV FIB 10.1 nm 100V 2.0μm 3.0° 0.1 500 μm MTU-Hannover Material Lab

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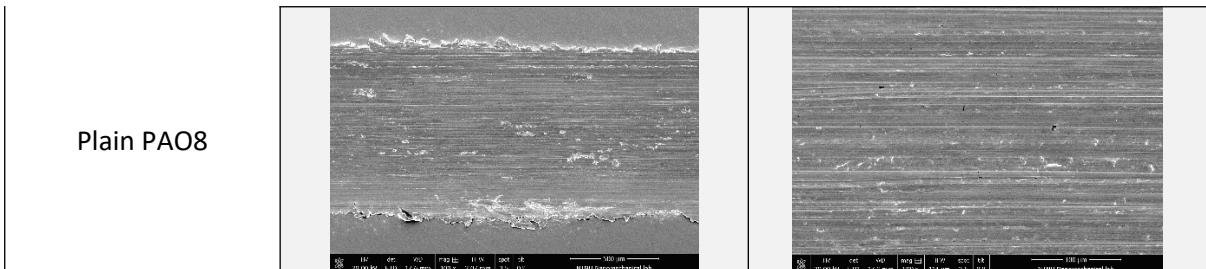


Supplementary information



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Plain PAO8



Supplementary information

All EDS mapping

1- SiW11THTDA at 1% in PAO8

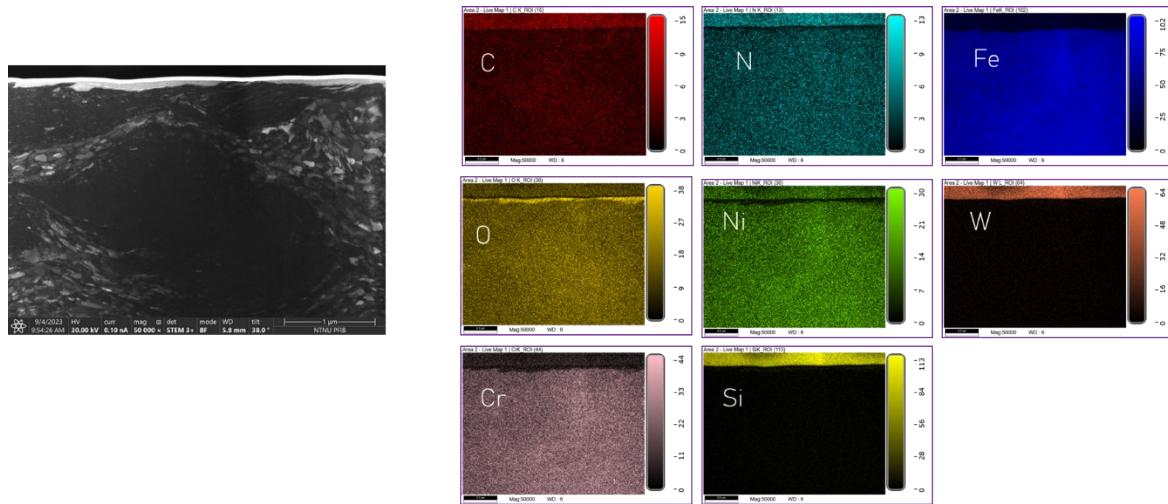


Figure S6. EDS mapping for different elements.

2- ZDDP at 1% in PAO8

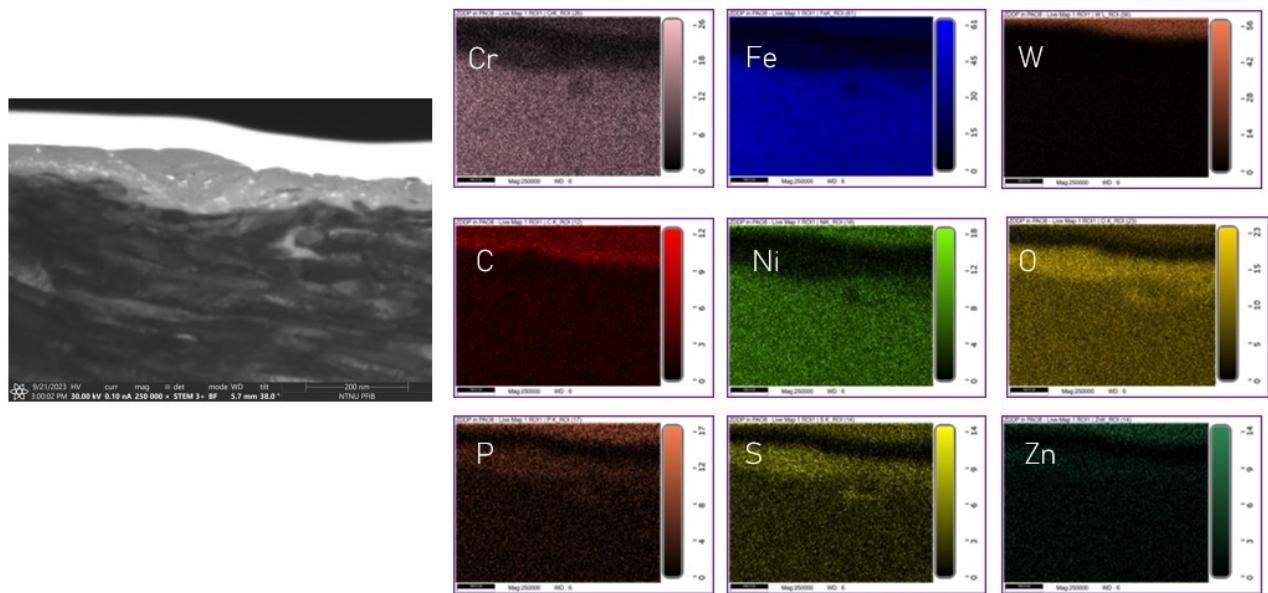


Figure S7. EDS mapping for different elements.

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TGA:

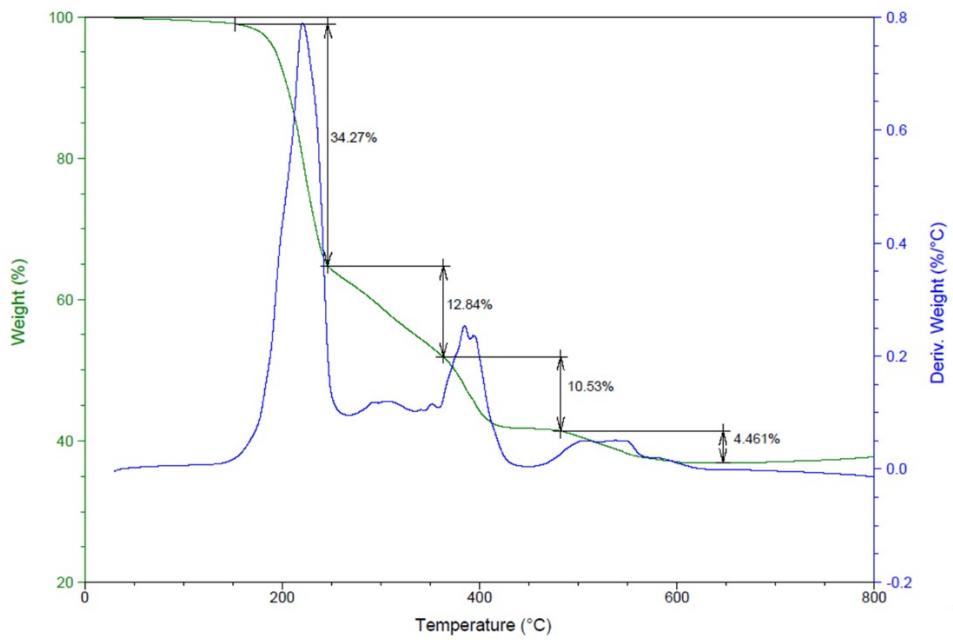


Figure S8. TGA analysis of SiW₁₁THTDA